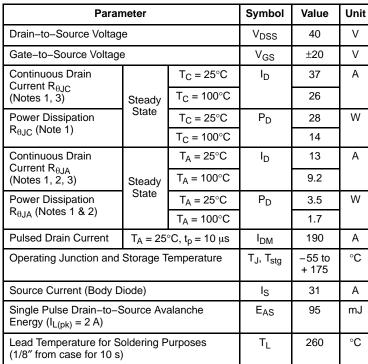
Power MOSFET 40 V, 10.3 mΩ, 37 A, Single N–Channel

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- NVMFS5C468NLWF Wettable Flank Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25° C unless otherwise noted)



Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	5.3	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{ extsf{ heta}JA}$	43	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
Maximum current for pulses as long as 1 second is higher but is do

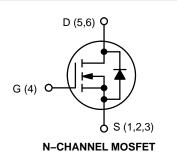
3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

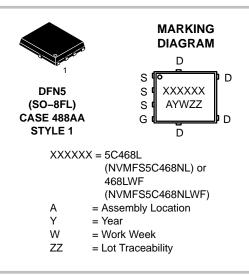


ON Semiconductor®

www.onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
40 V	10.3 mΩ @ 10 V	37 A
40 V	17.6 mΩ @ 4.5 V	51 A





ORDERING INFORMATION

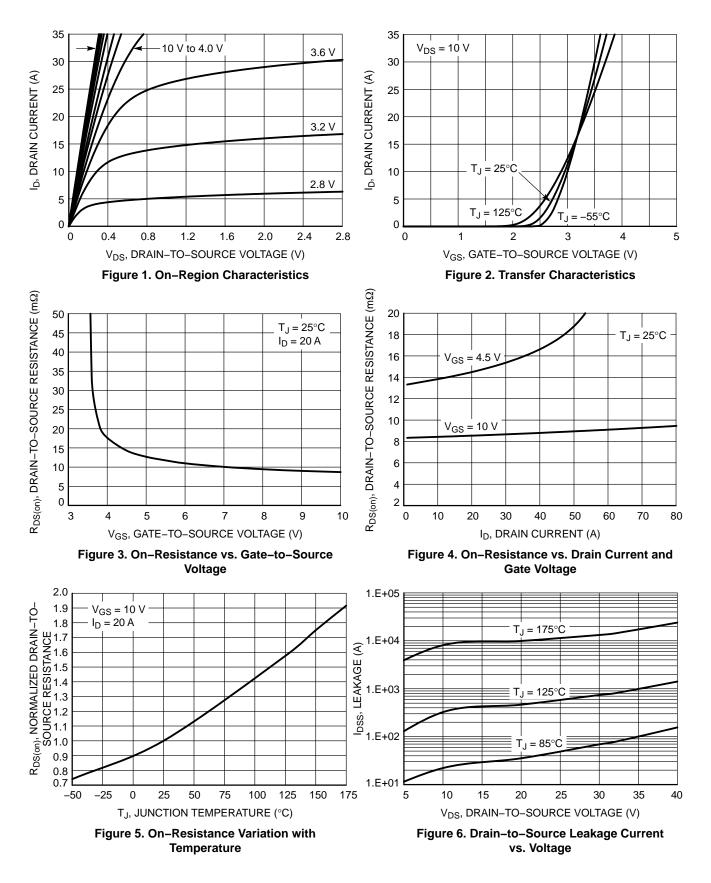
See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise specified)

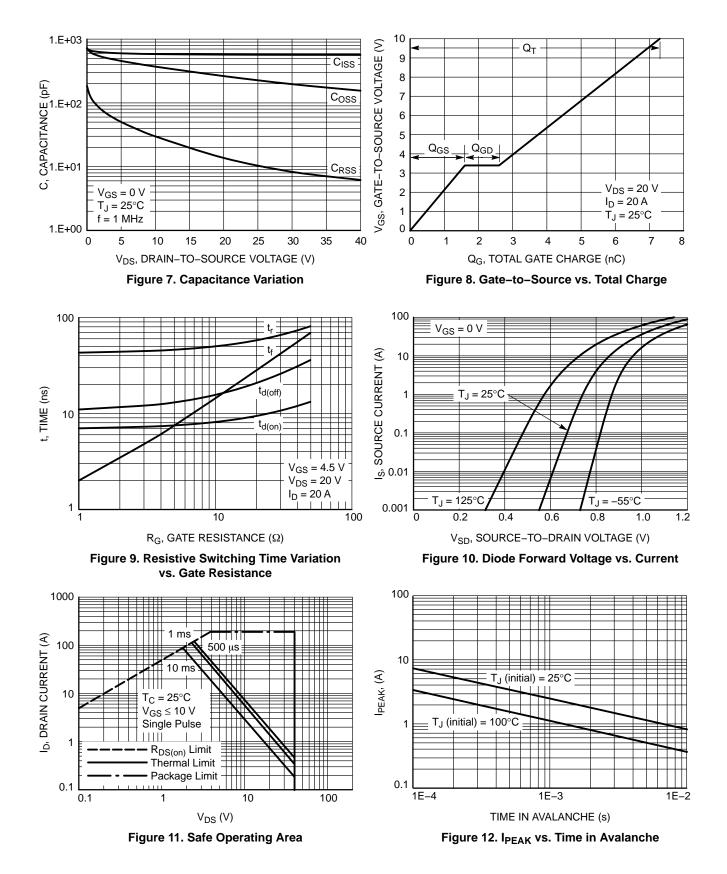
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 V, I_D =$	= 250 μA	40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				24		mV/∘C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25 °C			10	<u> </u>
		V _{DS} = 40 V	T _J = 125°C			250	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{G}$	_S = 20 V			100	nA
ON CHARACTERISTICS (Note 4)						-	
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D$	= 250 μA	1.2		2.0	V
Threshold Temperature Coefficient	V _{GS(TH)} /T _J				-4.8		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 20 A		8.6	10.3	1
		V _{GS} = 4.5 V	I _D = 20 A		14.5	17.6	mΩ
Forward Transconductance	9 FS	V _{DS} =15 V, I _I	₀ = 20 A		33		S
CHARGES, CAPACITANCES & GATE RE	SISTANCE						
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 25 V			570		pF
Output Capacitance	C _{OSS}				230		
Reverse Transfer Capacitance	C _{RSS}				11		
Total Gate Charge	Q _{G(TOT)}	V_{GS} = 10 V, V_{DS} = 20 V; I_{D} = 20 A			7.3		nC
Total Gate Charge	Q _{G(TOT)}				3.4		nC
Threshold Gate Charge	Q _{G(TH)}				0.9		1
Gate-to-Source Charge	Q _{GS}	V_{GS} = 4.5 V, V_{DS} = 20 V; I_{D} = 20 A			1.6		nC
Gate-to-Drain Charge	Q _{GD}				1.0		
Plateau Voltage	V _{GP}				3.4		V
SWITCHING CHARACTERISTICS (Note \$	ō)					-	
Turn-On Delay Time	t _{d(ON)}				7		-
Rise Time	t _r	V _{GS} = 4.5 V, V _I	ns = 20 V.		43		
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 20 \text{ A}, R_G = 1 \Omega$			11		- ns
Fall Time	t _f				2		
DRAIN-SOURCE DIODE CHARACTERIS	TICS				•		
Forward Diode Voltage	V _{SD}	$V_{GS} = 0 V,$ $I_{S} = 20 A$	$T_J = 25^{\circ}C$		0.88	1.2	- V
			T _J = 125°C		0.79		
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dI _S /dt = 100 A/µs, I _S = 20 A			18		ns
Charge Time	ta				9		
Discharge Time	t _b				9		
Reverse Recovery Charge	Q _{RR}				100		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Pulse Test: pulse width $\leq 300 \,\mu$ s, duty cycle $\leq 2\%$. 5. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS

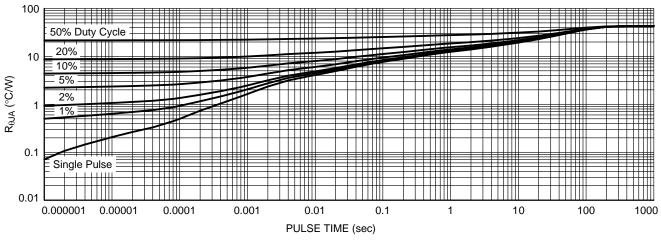
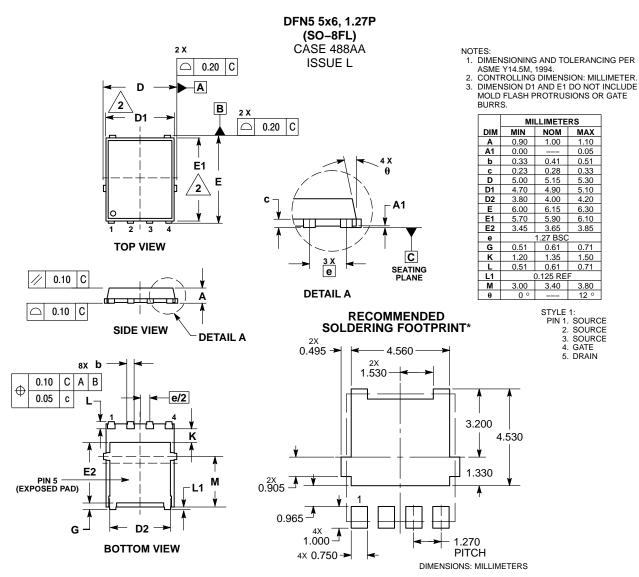


Figure 13. Thermal Characteristics

Device	Marking	Package	Shipping [†]
NVMFS5C468NLT1G	5C468L	DFN5 (Pb–Free)	1500 / Tape & Reel
NVMFS5C468NLWFT1G	468LWF	DFN5 (Pb–Free, Wettable Flanks)	1500 / Tape & Reel
NVMFS5C468NLT3G	5C468L	DFN5 (Pb–Free)	5000 / Tape & Reel
NVMFS5C468NLWFT3G	468LWF	DFN5 (Pb–Free, Wettable Flanks)	5000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS



*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ON Semiconductor and the intervent and the intervent of the pattern of the patter

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303–675–2175 or 800–344–3860 Toll Free USA/Canada Fax: 303–675–2176 or 800–344–3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support:

Phone: 421 33 790 2910 Japan Customer Focus Center Phone: 81–3–5817–1050 ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative